

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/623,880	BARNETT ET AL.	
Examiner	Art Unit	
Young J. Kim	1637	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
STIC - SEQ ID NO: 1 in Commercial, issued-patent, and PG-PUB databases.	9/14/2005	YJK		
Standard oligomer search; and length- limited oligomer search - size "19" for SEQ ID NO: 1 and size "20" for SEQ ID NO. 27.	9/14/2005	YJK		
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